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Test and Reliability of Electronic Circuits in Natural and Radiative Environment

Luigi Dilillo

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**HABILITATION À DIRIGER DES
RECHERCHES**

**Test and Reliability of Electronic Circuits in
Natural and Radiative Environment**

Rapport de

Luigi DILILLO

Chargé de Recherche au C.N.R.S.

Mai 2015

Preamble

The researches presented in this manuscript were performed between 2002 and 2015 at the laboratory LIRMM of Montpellier (France), the University of Southampton (ECS department) and the laboratory CEA LFSE of Saclay (France). This document consists of two main parts:

- The first part is an extended Curriculum Vitae, which includes details like collaborations, supervision, teaching activities, contracts, etc.
- The second part is a summary of my research activities and perspectives ending with bibliography references and the list of my publications.

The references of which I am not the author are indicated with a number that follows the order of appearance in the text. For example, [1] and [7] denote the first and the seventh publications that are referred in the document.

A different numbering was adopted to distinguish the work to which I contributed: publications in international journals are referenced by [JO#]; publications in international conferences, symposia and workshops are referenced by [CO#], [SY#] and [WO#] respectively.

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Table of Contents

A.1.	CURRICULUM VITAE	3
A.1.1.	Supervision of Students and Teaching activities	4
A.1.1.1.	Thesis Supervision	4
A.1.1.2.	Postdoc Supervision	5
A.1.1.3.	Supervision of Master and Engineering Students	6
A.1.1.4.	Teaching Activities at University of Montpellier	6
A.1.2.	academic and industrial collaborations, technology transfer	7
A.1.2.1.	Contacts with the Scientific Community and the Industry	7
A.1.2.2.	Participation To Research Contracts	9
A.1.3.	Coordination, Support and management of researches	9
A.1.3.1.	Member of Committee of International Conferences	9
A.1.3.2.	Member of Committee of National Conferences	10
A.1.3.3.	Session Chair in International Conferences	10
A.1.3.4.	Member of the Board of Scientific Organizations	11
A.1.3.5.	Organization of Sessions in International Conferences	11
A.1.3.6.	Reviewer Activity	11
A.2.	Summary of my Scientific Researches	13
A.2.1.	Context	13
A.2.2.	Basics of Test of Integrated Circuits and Systems, Radiation Test and Monitoring	14
A.2.2.1.	The Role of Test	14
A.2.2.2.	Types And Techniques Of Test	14
A.2.3.	Radiation Test and Radiation Monitoring	16
A.3.	Detail Of My Scientific Activity	19
A.3.1.	Test of Dynamic Faults in SRAM Memories	19
A.3.1.1.	Summary of the Studies on Dynamic Faults in SRAMs	26
A.3.2.	Low Power Test of Digital Circuits and Memories	28
A.3.3.	Impact of Radiation on Digital Circuits	32
A.3.3.1.	Basic Mechanisms of Soft Errors	33
A.3.3.2.	Proposed Framework For Simulation Level Testing Testing of Radiation Effects	35
A.3.3.3.	Accelerated test	37
A.3.4.	Radiation Monitoring	42
A.3.4.1.	SRAM Based Monitor for Mixed-Field Radiation Environments	43
A.3.4.2.	Real-Time Testing of 90nm COTS SRAMs at Concordia Station in Antarctica	45
A.3.5.	Space and Radiation Hardened Systems Design	48
A.4.	Research Perspectives	50
A.4.1.	Monitoring of High Temperature Effects of CMOS Circuits	50
A.4.2.	Design and Characterization of Radiation-Hardened Front-end Electronic Systems	50
A.4.3.	Test and Reliability of Low Power SRAM Memories in Deep nanoscale technology	51
A.4.4.	Medium and Long Term Plans	52
A.5.	Personal publications	53
A.6.	Bibliography	62